



optical thickness measurement µ-thick and m-thick systems

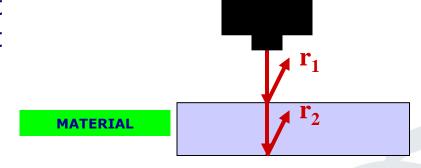




how does it work?

patented by **Nirox srl**, it represents the latest measuring solution available on the market to optically measure thickness.

the measure is based on the light reflected at entrance and exit interfaces $(r_1 e r_2)$.



BROAD-BAND

LIGHT SOURCE

optical head collect both reflections and make it possible to obtain interference between them.

the resulting optical signal intensity has a component directly related to the physical thickness *d* and the index of refraction *n* of the material.





applications

materials measured: any transparent or semitransparent material (colours and/or particular surface finish need specific testing); coating on substrates

what is measured: total thickness of a single or multi layer structure; thickness of a single layer coated on glass/metal. Layer discrimination of sandwich structure is under development

target markets

- plastic material extrusion
- glass production lines (flat, hollow)
- coating on glass or metal substrates
- medical plastic devices
- coating on optical devices
- semiconductors, photo resist and oxides





main advantages

- ✓ one-sided measure (reflection)
- √ high accuracy
- ✓ non-contact, non destructive measurement
- ✓ light used is not dangerous
- ✓ easy to use
- ✓ quick integration in laboratory and production lines





technical specs.

cnocification	μ-Thick		m-Thick	
specification	EP1	EP2	EP3	EP4
measurement rate [measurements /sec.]	120			
light source	halogen	en SLD		
accuracy	<0.1 micron			
maximum thickness [micron] (n=1.5)	100	380	1800	4000
measuring spot dimension	2 mm	0.05 mm		
working distance [mm]	40			
working distance range [mm]	±5 mm	±2.5 mm		





system configuration

	code	description	application		
	МТ	optical head is fiber-optic connected to the measuring unit that is equipped with processing electronics	lab or		
	MI	the measuring unit provide thickness data output through analog/digital connection	production		
	HI	"all inside the box": the measuring unit is equipped with optical head and processing electronics the measuring unit provide thickness data output through analog/digital connection	lab or production		



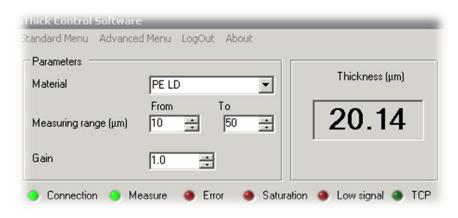


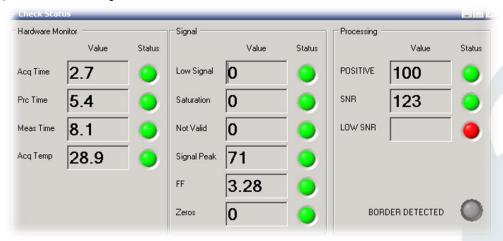
software interface

user-friendly interface
(measuring unit)

thickness calculation and raw-measurement statistics

digital data output management with supervisor system (TCP/IP, RS485)







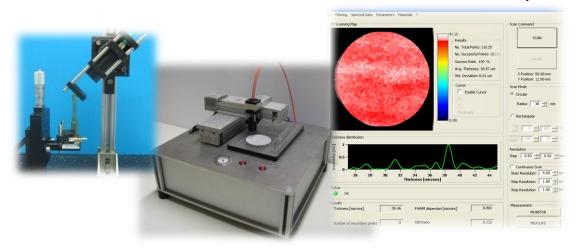
system options

distributed optical heads: a single measuring unit with an optical switch can drive several optical heads for distributed measurements

supervisor software: real-time data display and production data management

laboratory scanner: delivery of stand-alone unit with motorized x-y positioning system for measurement of thickness profile (1D) or maps (2D)

custom software: software customization for specific needs



contact us

for additional information and free sample testing contact



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